



NREL

National Renewable Energy Laboratory

Innovation for Our Energy Future

MODELING Cu MIGRATION IN CdTe SOLAR CELLS UNDER DEVICE-PROCESSING AND LONG-TERM STABILITY CONDITIONS

Glenn Teeter and Sally Asher

National Renewable Energy Laboratory • Golden, CO 80401

Abstract

An impurity migration model for systems with material interfaces is applied to Cu migration in CdTe solar cells. In the model, diffusion fluxes are calculated from the Cu chemical potential gradient. Inputs to the model include Cu diffusivities, solubilities, and segregation enthalpies in CdTe, CdS and contact materials. The model yields transient and equilibrium Cu distributions in CdTe devices during device processing and under field-deployed conditions. Preliminary results for Cu migration in CdTe PV devices using available diffusivity and solubility data from the literature show that Cu segregates in the CdS, a phenomenon that is commonly observed in devices after back-contact processing and/or stress conditions.

Diffusion-Segregation Model: Pseudo-Binary Diffusion Couple Formulation

Free Energy

$$A = \sum_i [(n_i X_{Cu}^i) \mu_{Cu}^i + (n_i X_p^i) \mu_p^i]$$

POhenomenological Flux Eq.

$$J_{Cu} = -MC_{Cu} \frac{\partial \mu_{Cu-p}}{\partial x}$$

Mobility

$$M = \frac{D}{kT} \frac{C_p}{C_0}$$

Chemical Potential

$$\mu_{Cu-p}^i = \frac{1}{n_i} \frac{\partial A}{\partial X_{Cu}^i} = \Delta H_{Cu-p}^i + kT \ln \frac{X_{Cu}^i}{1 - X_{Cu}^i}$$

Migration Flux

$$J = \frac{C_p}{C_0} \left(\frac{DC}{kT} \frac{\partial \phi_{Cu-p}}{\partial x} - C \frac{\partial D}{\partial x} \right) - D \left(\frac{\partial C}{\partial x} - \frac{C}{C_0} \frac{\partial C_0}{\partial x} \right)$$

Migration Potential

$$\Delta H_{Cu-p}^i = -(E_D^i + \phi_{Cu-p}^i)$$

Segregation Enthalpy

$$H_{seg} = \Delta H_{Cu-p} - \Delta H_{Cu-p'}$$

Continuity Equation

$$\frac{\partial C}{\partial t} = -\frac{\partial J}{\partial x}$$

Fick's 1st Law

$$J = -D(\partial C / \partial x)$$

Migration Potential Near a Pseudo-Binary Diffusion Couple Interface

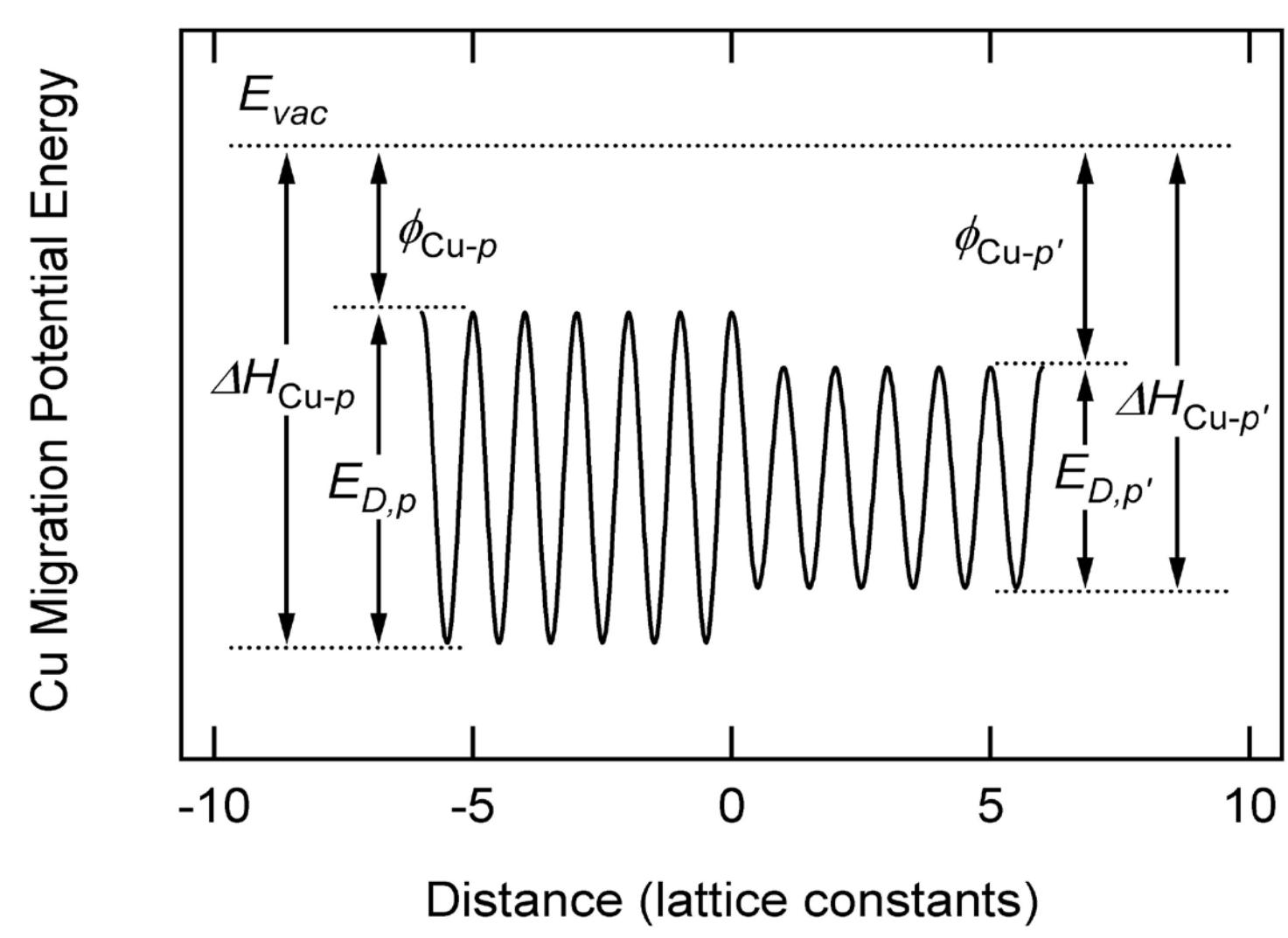


Figure 1. Schematic illustration of the ideal-solution Cu migration potential near a hypothetical material interface.

Device-Processing Simulation Results: High-Diffusivity Case

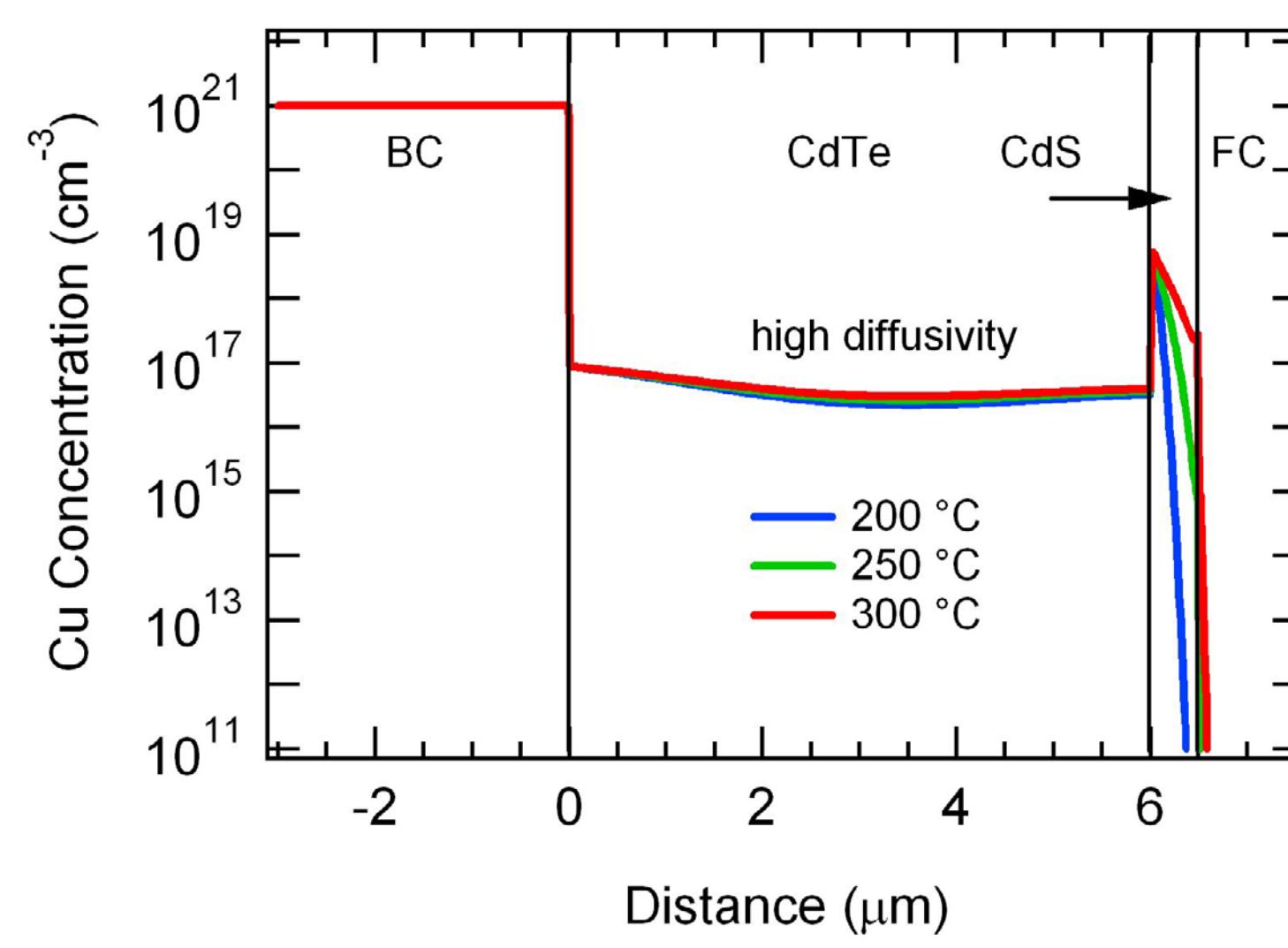


Figure 2. Device-processing simulation of Cu migration in CdTe PV device for the high-diffusivity case.

Device-Processing Simulation Results: Low-Diffusivity Case

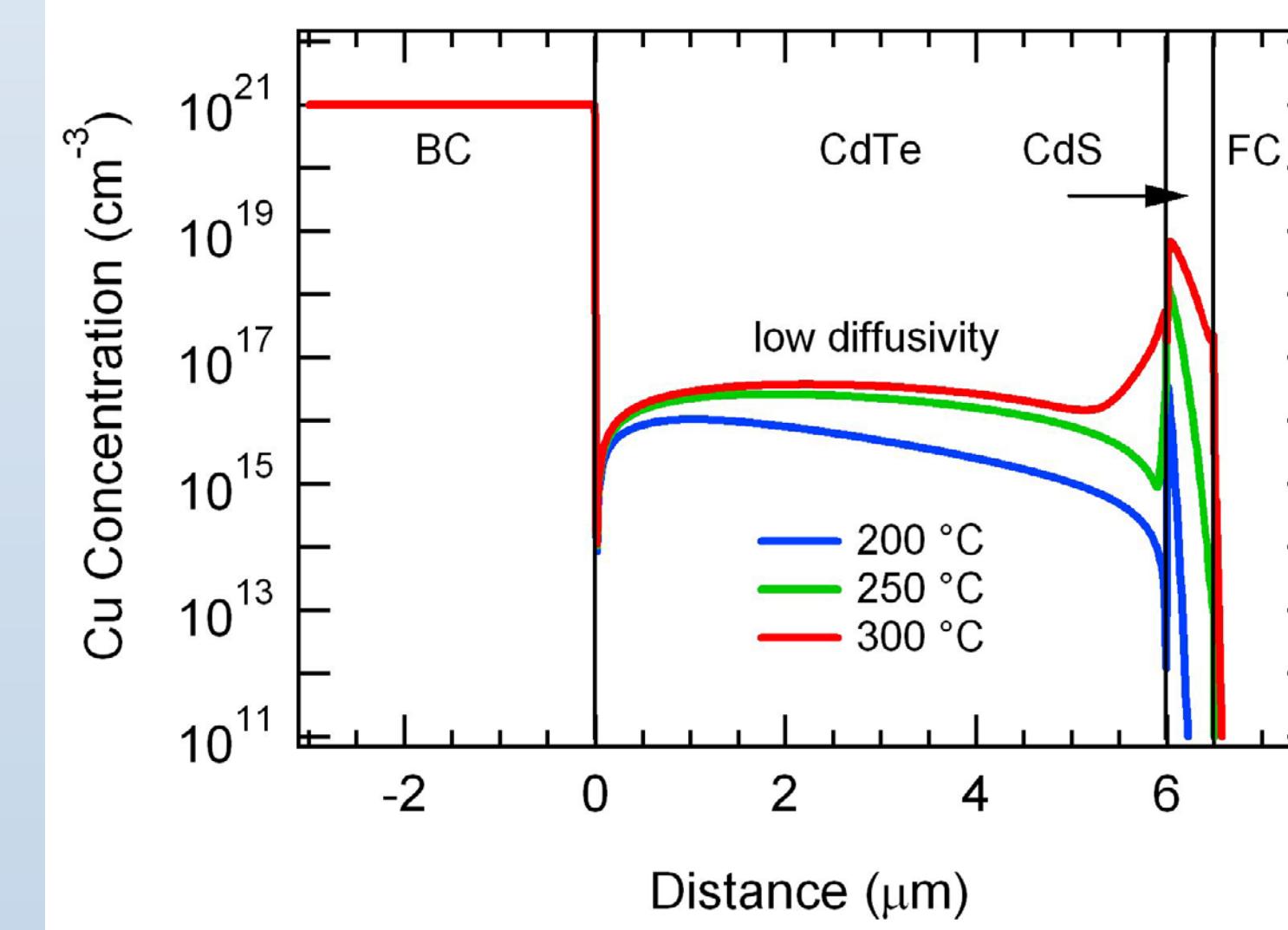


Figure 3. Device-processing simulation of Cu migration in CdTe PV device for the low-diffusivity case.

Survey of Cu Diffusivities and Solubilities in CdTe and CdS

| CdTe:Cu diffusivity data | | | |
|---------------------------------------|-------------|------|----------|
| D_0 ($\text{cm}^2 \text{s}^{-1}$) | E_D (eV) | Ref. | SC or PX |
| 1.70E-06 | 0.24 | [1] | |
| 6.65E-05 | 0.57 | [2] | SC |
| 7.30E-07 | 0.33 | [3] | |
| 1.30E-06 | 0.29 | [4] | PX |
| 8.20E-08 | 0.64 | [5] | |
| 3.70E-04 | 0.67 | [6] | |
| 9.57E-04 | 0.7 | [7] | |

| CdTe:Cu solubility data | | | |
|----------------------------|-------------|------|----|
| C_0 (cm^{-3}) | E_a (eV) | Ref. | |
| 1.56E+23 | 0.55 | [2] | SC |
| -2E+17 | -0 | [4] | PX |
| 3.73E+24 | 0.68 | [8] | |

| CdS:Cu diffusivity data | | | |
|---------------------------------------|------------|------|----|
| D_0 ($\text{cm}^2 \text{s}^{-1}$) | E_D (eV) | Ref. | |
| 1.20E-02 | 1.05 | [9] | SC |
| 2.10E-03 | 0.96 | [10] | SC |
| 1.60E-03 | 0.77 | [11] | SC |
| — | 0.95 | [12] | SC |
| 6.00E-09 | 0.5 | [13] | PX |
| — | 1.0 | [14] | SC |

| CdS:Cu solubility data | | | |
|----------------------------|-------------|------|----|
| C_0 (cm^{-3}) | E_a (eV) | Ref. | |
| 8.00E+21 | 0.27 | [13] | PX |
| 6.60E+22 | 0.505 | [10] | SC |

Long-Term Stability Simulation Results: High-Diffusivity Case

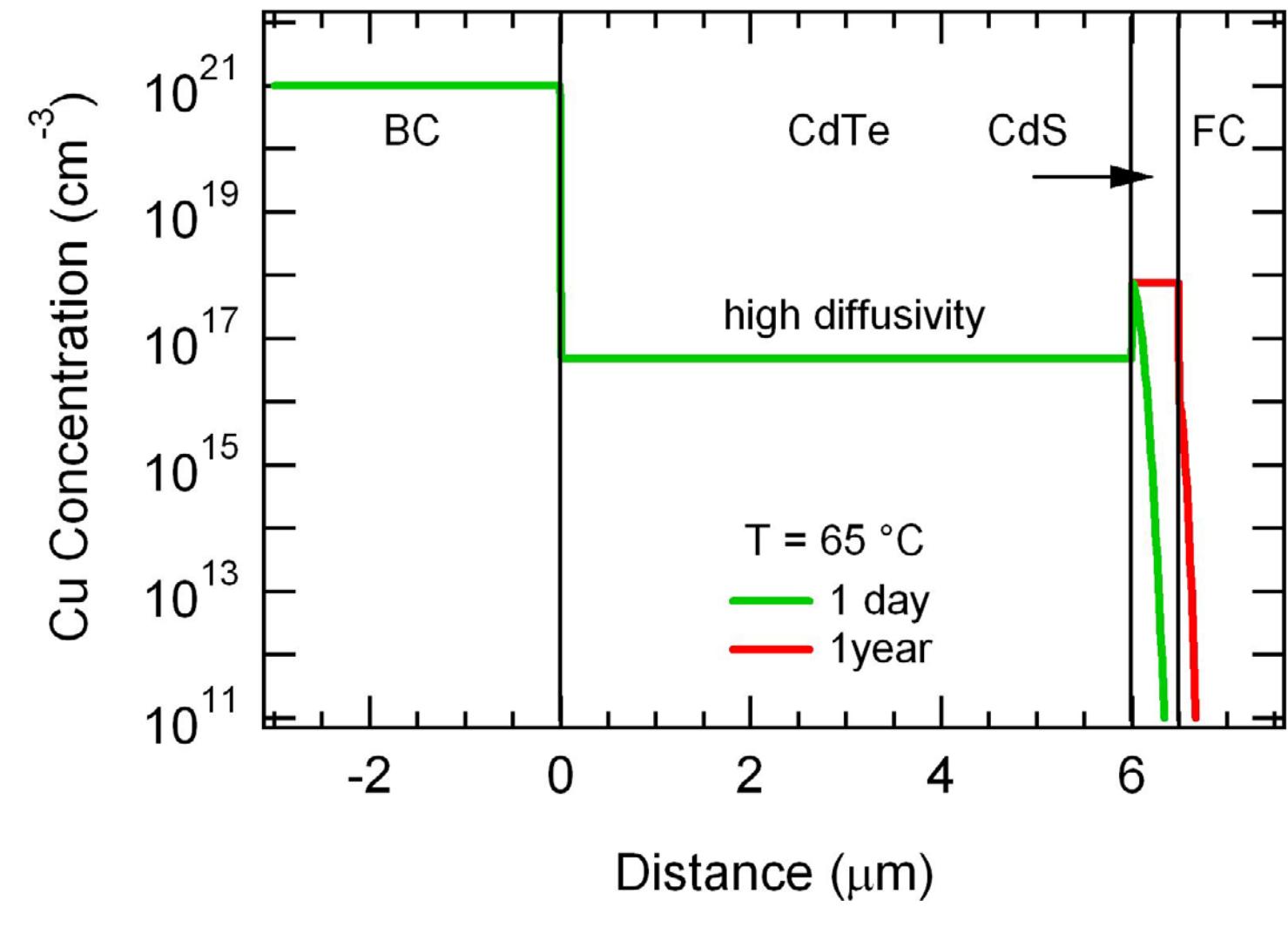


Figure 4. Long-term stability simulation of Cu migration in CdTe PV device for the high-diffusivity case.

Long-Term Stability Simulation Results: Low-Diffusivity Case

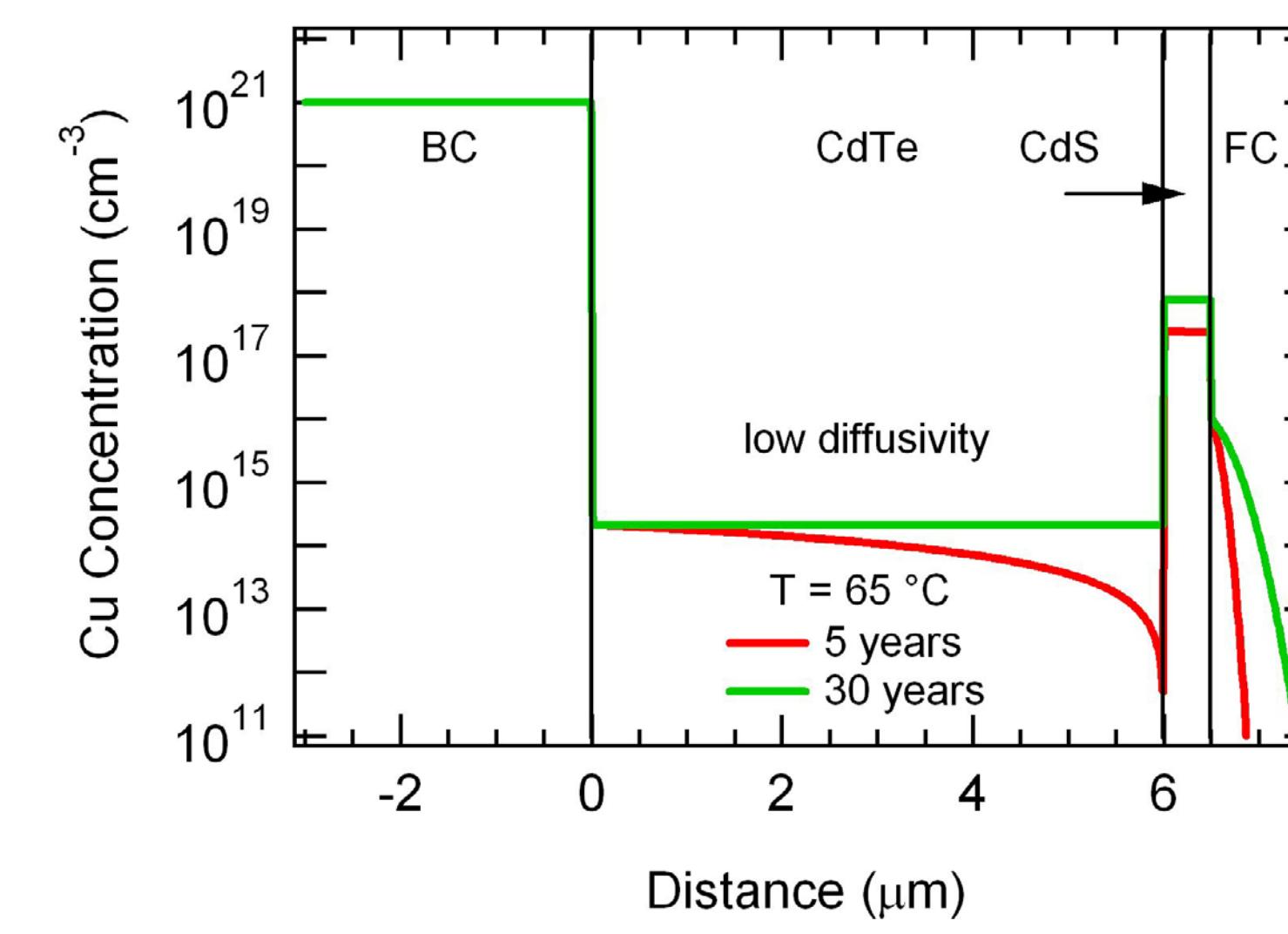


Figure 5. Long-term stability simulation of Cu migration in CdTe PV device for the low-diffusivity case.

SIMS Depth Profile

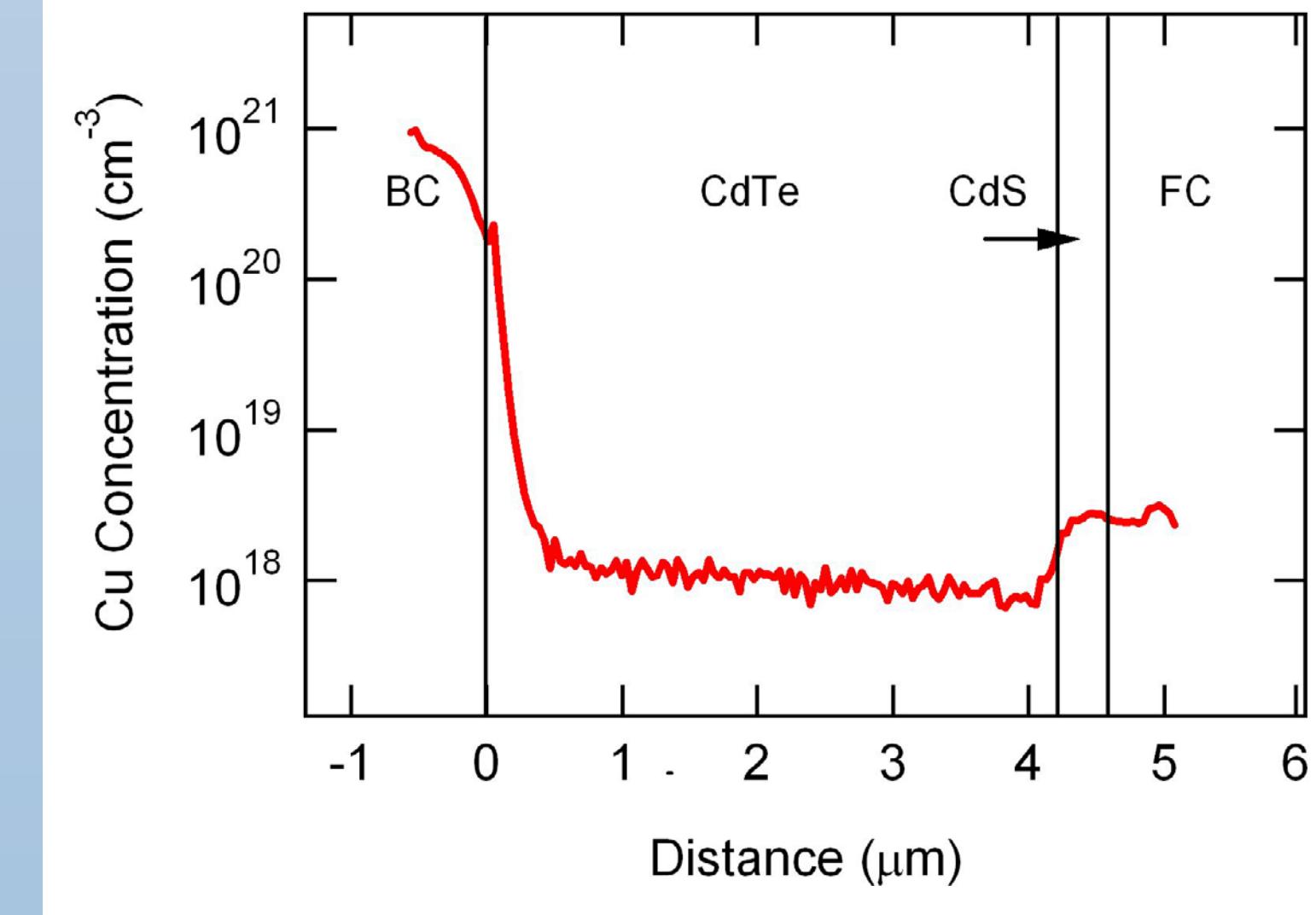


Figure 6. Typical SIMS profile of a ZnTe:Cu back-contacted device after back-contact processing.

REFERENCES

- [1] O. Warlick, C. Blanchard, and J. F. Barth, "Study of silver and copper diffusion in n-type CdTe sub 0.7Te and CdTe by capacitance measurements," *Materials Science & Engineering B (Solid-State Materials for Advanced Technology)*, vol. B71, pp. 254-257, 2000.
- [2] E. V. Vashchenko, N. M. Yermakova, and V. M. Murashov, "Kinetics of diffusion of Cu in CdTe," *Journal of Crystal Growth*, vol. 117, pp. 249-253, 1991.
- [3] D. Dzhafarov, S. S. Yesilayeva, N. Carli, and M. Caliskan, "Diffusion and influence of Cu on properties of CdTe thin films and CdTe/CdS cells," *Solar Energy Materials and Solar Cells*, vol. 85, pp. 371-383, 2003.
- [4] R. A. Erzenkov, K. L. Barth, and W. S. Sampath, "Transient ion drift measurements for polycrystalline CdTe PV devices," *Conference Record of the 2006 IEEE 4th World Conference on Photovoltaic Energy Conversion (IEEE Cat. No. 06CH37747)*, pp. 4-4, 2006.
- [5] H. G. Lintermann, D. G. Linder, and O. Meyer, "Annealing processes at the Cd-CuTe interface for thermal and chemically plated CdTe," *Solid State Communications*, vol. 11, pp. 475-479, 1972.
- [6] J. W. Weimer and M. M. Kim, "Diffusion of Cu in CdTe," *Journal of Applied Physics*, vol. 39, pp. 5465-5468, 1968.
- [7] O. E. Panczak, V. I. Gryazev, and D. P. Peteloski, "Diffusion of Cu in CdTe," *Inorganic Materials*, vol. 11, pp. 1510-1512, 1975.
- [8] V. V. Vishnyakov, V. N. Zubkovskaya, and T. V. Kulikova, "Solubility of copper in cadmium telluride," *Inorganic Materials*, vol. 25, pp. 502-505, 1989.
- [9] J. L. Sullivan, "Diffusion and Solubility of Cu in CdS Single Crystals," *Physical Review*, vol. 184, pp. 798-805, 1969.
- [10] J. L. Sullivan, "Diffusion of Copper in Cadmium Sulfide Crystals," *Journal of Applied Physics*, vol. 30, pp. 957-960, 1959.
- [11] R. L. Clarke, "Diffusion of Copper in Cadmium Sulfide Crystals," *Journal of Applied Physics*, vol. 33, pp. 232-236, 1962.
- [12] J. L. Sullivan, "Effect of Annealing on the Nature of Diffusion Anisotropy in CdS Crystals," *Semiconductor Physics Quantum Electronics & Optoelectronics*, vol. 3, pp. 292-296, 2000.
- [13] E. B. Kaganovich, I. K. Ostrovskaya, Y. S. Pilipuk, and E. M. Pochtar, "Diffusion and solubility of copper in photodeposited CdS films precipitated from aqueous solution," *Inorganic Materials*, vol. 24, pp. 1238-1239, 1988.
- [14] L. V. Borkovska, L. Y. Khomenko, N. E. Korunskaya, I. V. Markevich, and M. K. Sheinkman, "Some peculiarities of impurity diffusion in CdS crystals," *Physica Status Solidi B*, vol. 229, pp. 269-273, 2002.